| Ref<br># | Hits | Search Query   | DBs   | Default<br>Operator | Plurals | Time Stamp       |
|----------|------|--|---|---------------------|---------|------------------|
| Ľ1       | 396  | (high adj dielectric adj constant)<br>near5 (barrier)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:07 |
| L2       | 19   | (high adj dielectric adj constant<br>adj film) near5 (barrier)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:07 |
| L3       | 6    | (high adj dielectric adj constant<br>adj film) near5 (barrier adj film)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:12 |
| L4       | 19   | (yoshinao near harada)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:10 |
| L5       | 7    | (high adj dielectric adj constant<br>adj film) near10 (barrier adj film)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:12 |
| L6       | 3    | (high adj dielectric adj constant<br>adj film) near10 (barrier adj film)<br>same metal same oxygen same<br>silicon | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:13 |
| L7       | 3    | (high adj dielectric adj constant)<br>near10 (barrier adj film) same<br>metal same oxygen same silicon             | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:13 |
| L8       | 38   | (high adj dielectric adj constant)<br>near10 (barrier) same metal same<br>oxygen same silicon                      | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:13 |
| L9       | 38   | ((high adj dielectric adj constant)<br>near10 (barrier)) same metal<br>same oxygen same silicon                    | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR                  | ON      | 2005/02/03 13:13 |

| L10  | 13     | ((high adj dielectric adj constant)<br>near10 (barrier)) with metal same<br>oxygen same silicon                                | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:13 |
|------|--------|--|---|----|----|------------------|
| LH   | 8      | ((high adj dielectric adj constant)<br>near10 (barrier)) with metal with<br>oxygen same silicon                                | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:13 |
| L12  | 879966 | ((high adj dielectric adj constant)<br>near10 (barrier)) with metal with<br>oxygen wityh silicon                               | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:13 |
| 1.13 | 6      | ((high adj dielectric adj constant)<br>near10 (barrier)) with metal with<br>oxygen with silicon                                | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:15 |
| L14  | 0      | ((high adj dielectric adj constant)<br>near10 (barrier)) and MSiON   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:15 |
| L15  | 3      | ((high adj dielectric adj constant)<br>near10 (barrier)) and (M near2 Si<br>near2 O near2 N)                                   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:16 |
| L16  | 3      | (((high adj dielectric adj constant)<br>or (high near k) or (high-k))<br>near10 (barrier)) and (M near2 Si<br>near2 O near2 N) | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:17 |
| L17  | 88     | (((high adj dielectric adj constant)<br>or (high near k) or (high-k))<br>near10 (barrier)).clm.                                | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:18 |
| L18  | 4      | (((high adj dielectric adj constant)<br>or (high near k) or (high-k))<br>near10 (barrier)).clm. and Hf and<br>SiON             | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/02/03 13:19 |